Title: Datasheet update for BQ24196 Customer Contact: PCN Manager Dept: Quality Services Change Type: Assembly Site Design Wafer Bump Site Wafer Bump Site Wafer Bump Material Assembly Process Data Sheet Wafer Bump Material Assembly Materials Part number change Wafer Bump Process Mechanical Specification Test Site Wafer Fab Site Wafer Bump Process Part number change Wafer Bump Process Part number change Wafer Bump Process Part number change Wafer Fab Site Wafer Fab Site Wafer Fab Site Packing/Shipping/Labeling Test Process PCN Details Person Details Details Person Details Person Details Person Details Person Details Person Detail	PCN	Number:	201501230	00			PCN Date:	01/28/2015
Change Type:	Title:	Datasheet u	pdate for BQ2	4196				
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These changes may be reviewed at the datasheet links provided.

http://www.ti.com/sitesearch/docs/universalsearch.tsp?searchTerm=BQ24196#linkId=1&src=top

Reason for Change:						
To more accurately reflect device characteristics.						
Anticipated impact on Fit, Form, Function, Quality or Reliability (positive / negative):						
Electrical specification performance changes as indicated above.						
Changes to product identification resulting from this PCN:						
None.						
Product Affected:						
BQ24196RGER	BQ24196RGET					

For questions regarding this notice, e-mails can be sent to the regional contacts shown below or your local Field Sales Representative.

Location	E-Mail
USA	PCNAmericasContact@list.ti.com
Europe	PCNEuropeContact@list.ti.com
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